

COMMON BROKERAGE EVENT

15 – 16 October 2009

Brussels

Equipment, Materials & Manufacturing

Plenary Feedback

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MASP 4 Grand Challenges in EMM

Field 1: „Direct Impact“

- EUV & complementary 1Xnm patterning
- 450mm supply chain

Field 2: „Strategic“

- “More Moore” innovations
- “More than Moore” innovations

Topics for EoI: Mask

Name	Subject	Companies	Contact
Mask	Mask metrology for 22nm and beyond Pattern Placement Metrology EUV Metrology and Repair	Carl Zeiss, Toppan, Vistec	h.feldmann@smt.zeiss.com
Mask	E-Beam Patterned Mask Inspection	AMIL, ASML, Toppan, Synch. Trieste, IMEC	Yoram_Uziel@amat.com
Mask	Push Optical Litho to Limit (193nm and 248nm): Patterning Process Control Mask Utilization (Contamination	Toppan	michel.tissier@photomask.com

Topics for Eol: Metrology

Name	Subject	Companies	Contact
InSitu Metrology	Integrated InSitu Metrology in Semiconductor Equipments	Infineon, Semilab, FhG, Numonyx, TNO, Synch. Trieste, Austriamicr osystems	ahmad.fathulla@infineon.com
Data	Significance and Validity of Data in Extremely Heterogeneous Fabrication	Infineon, Numonyx, TNO, Toppan	ahmad.fathulla@infineon.com

Topics for EoI: Process

Name	Subject	Companies	Contact
Carbon	Bulk Carbon Processes for Semiconductor Applications	Infineon, Sync. Trieste, TNO, Semilab, U. Lovain, FhG,	ahmad.fathulla@infineon.com
FE/BE Integration	Alternatives for Metallization and Passivation: Printing?	Infineon, TNO, FhG	ahmad.fathulla@infineon.com
Zero Kerf	New Dicing process w/o Silicon Damage	Infineon, ALSI, FhG	ahmad.fathulla@infineon.com

Topics for Eol: Wafer test

Name	Subject	Companies	Contact
Automation	Automation of Wafer Test: Less error, better yield, better utilization, less cost	Infineon, Recif	ahmad.fathulla@infineon.com
APC	APC/SPC in wafer test	Infineon, FhG	ahmad.fathulla@infineon.com

Topics for Eol: Green Fab

Name	Subject	Companies	Contact
Green Fab	Towards zero impact manufacturing Saving energy, water Replace dangerous chemicals	Numonyx, AMIL, Alcatel, Soitec, Toppan, TNO, Infineon	livio.baldi@numonyx.com

Topics for Eol: 450mm

Name	Subject	Companies	Contact
450mm	450nm Sol wafers and related processes	Soitec	nelly.kernevez@soitec.fr
450mm	Automated Wafer handling system Increase speed, new environment specs	Recif, HAP, Oxford Instr., Sysmecca, AIS, FhG, ASM, Vistec	florent.haddad@recif.com